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Substitute for form 1449A/PTO				Complete if Known	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>				Application Number	10/629,015
(use as many sheets as necessary)				Filing Date	July 29, 2003
				First Named Inventor	Kimberley Kuhlman
				Art Unit	2881
				Examiner Name	Nguyen, Ket Tuan
Sheet	1	of	2	Attorney Docket Number	CIT.PAU.39 A



## **INFORMATION DISCLOSURE STATEMENT BY APPLICANT**

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Sheet 1 of 2

## **FOREIGN PATENT DOCUMENTS**

Examiner Signature	K. MURYEN	Date Considered	09-05-04
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**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

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Sheet

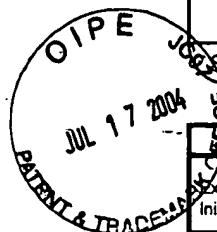
2

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**Complete if Known**

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**OTHER-PRIOR ART – NON PATENT LITERATURE DOCUMENTS**

Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
lcv		Preparation of 3D Atom Probe Samples of Multilayered Film Structures Using a Focused Ion Beam R. L. Martens, D. J. Larson, T. F. Kelly, A. Cerezo, P. H. Clifton and N. Tabat Pages 522-523 – 2000	
lcv		Focused ion-beam specimen preparation for atom probe field-ion microscopy characterization of multilayer film structures D. J. Larson, D. T. Foord, A. K. Petford-Long, A. Cerezo and G. D. W. Smith Pages 45-50, May 16, 1998	
lcv		Three-dimensional atom probe field-ion microscopy observation of Cu/Co multilayer film structures D.J. Larson, A. K. Petford-Long, A. Cerezo and G. D. W. Smith Pages 1125-1127, Volume 73, Number 8, Applied Physics Letters, 24 August 1998	
lcv		Advances in Atom Probe Specimen Fabrication from Planar Multilayer Thin Film Structures D. J. Larson, B. D. Wissman, R. L. Martens, R. J. Viellieux, T. F. Kelly, T. T. Gribb, H. F. Erskine and N. Tabat, Pages 24-31, September 18, 2000	

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